

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination GERLT ET AL.	
		10/541,815	Examiner	Art Unit Matthew W. Such 2891

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,958,270	10-2005	Misra et al.	438/257
*	C	US-6,908,536	06-2005	Beckmann, Udo	204/412
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*	E	US-2003/0087533	05-2003	Stupp et al.	438/745
*	F	US-5,942,388	08-1999	Willner et al.	435/6
*	G	US-7,074,519	07-2006	Kuhr et al.	429/149
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**NON-PATENT DOCUMENTS**

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	U	Roth, K.M, et al. "Characterization of Charge Storage in Redox-Active Self-Assembled Monolayers." LANGMUIR, Vol. 18 (2002): pp. 4030-4040.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.